

In the Claims:

1. (Currently amended) A device comprising:
a heat sink; and
a radiation-emitting optoelectronic component (1) which is connected to [[a]] said heat
sink (3) and is intended for pulsed operation with the pulse duration D,
wherein said heat sink is arranged such that temperature changes of the optoelectronic
component ~~taking take~~ place with a thermal time constant τ during pulsed operation, and
~~characterized in that~~ wherein the thermal time constant τ is matched to the pulse duration
D in order to reduce the amplitude of the temperature changes.

2. (Currently amended) The ~~optoelectronic component~~ device as claimed in claim
1,
~~characterized in that~~ wherein
the thermal time constant τ is $\tau > 0.5 D$ for.

3. (Currently amended) The ~~optoelectronic component~~ device as claimed in claim
1,
~~characterized in that~~ wherein
the thermal time constant τ is $\tau > D$.

4. (Currently amended) The ~~optoelectronic component~~ device as claimed in claim
1, one of claims 1 to 3,
~~characterized in that~~ wherein

the temperature changes are less than $\Delta T = 12$ K.

5. (Currently amended) The ~~optoelectronic component~~ device as claimed in claim
1, one of the preceding claims,
characterized in that wherein
pulsed operation is effected at a pulse frequency in the range from 0.1 Hz to 10 Hz.

6. (Currently amended) The ~~optoelectronic component~~ device as claimed in claim
1, one of the preceding claims,
characterized in that wherein
~~it~~ the optoelectronic component has an optical output power of 20 W or more.

7. (Currently amended) The ~~optoelectronic component~~ device as claimed in claim
1, one of the preceding claims,
characterized in that wherein
the heat sink ~~(3)~~ is actively cooled.

8. (Currently amended) The ~~optoelectronic component~~ device as claimed in claim
7,
characterized in that wherein
the heat sink ~~(3)~~ has one or more microchannels ~~(6)~~ through which a coolant flows.

9. (Currently amended) The ~~optoelectronic component~~ device as claimed in claim 8,
~~characterized in that~~ wherein
a wall of the heat sink that adjoins the optoelectronic component (1) has a wall thickness (7) of 0.5 mm or more.

10. (Currently amended) The ~~optoelectronic component~~ device as claimed in claim 8,
~~characterized in that~~ wherein
a wall of the heat sink that adjoins the optoelectronic component (1) has a wall thickness (7) of between 1 mm and 2 mm inclusive.

11. (Currently amended) The ~~optoelectronic component~~ device as claimed in claim 1, one of the preceding claims,
~~characterized in that~~ wherein
the heat sink (3) contains copper.

12. (Currently amended) The ~~optoelectronic component~~ device as claimed in claim 1, one of the preceding claims,
~~characterized in that~~ wherein
the optoelectronic component (1) is a laser diode bar.

13. (Currently amended) A method for producing ~~an optoelectronic component~~ the device as claimed in claim 8 ~~one of claims 8 to 12~~,

~~characterized in that~~ wherein

a wall of the heat sink (3) that adjoins the optoelectronic component (1) has a wall thickness (7) and the temperature change and/or the maximum temperature of the component (1) during operation is set by dimensioning the wall thickness (7).

14. (Currently amended) A method for producing a device having a radiation-emitting optoelectronic component (1) which is connected to a heat sink (3) and is intended for pulsed operation with the pulse duration D, temperature changes of the optoelectronic component taking place with a thermal time constant τ during pulsed operation, the method comprising:

~~characterized in that~~

setting the thermal time constant τ ~~is matched~~ to match the pulse duration D in order to reduce the amplitude of the temperature change.

15. The method as claimed in claim 14,

~~characterized in that~~ wherein

the thermal time constant τ is set by dimensioning the area and/or the thickness of a substrate on which the optoelectronic component (1) is produced.